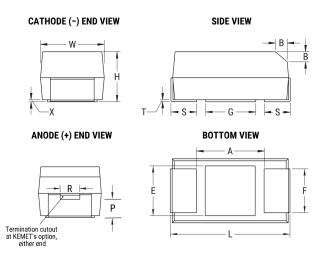


T493C106K016CH6420

T493 HRA, Tantalum, MnO2 Tantalum, HRA, 10 uF, 10%, 16 VDC, SMD, MnO2, Molded, High Reliability, C (0.01%/1000 Hrs), 600 mOhms, 6032, Height Max =



Click	here	for	the	3D	model

Dimensions	
Footprint	6032
L	6mm +/-0.3mm
W	3.2mm +/-0.3mm
Н	2.5mm +/-0.3mm
Т	0.13mm REF
S	1.3mm +/-0.3mm
F	2.2mm +/-0.1mm
Α	3.1mm MIN
В	0.5mm +/-0.15mm
E	2.4mm REF
G	2.8mm REF
Р	0.5mm MIN
R	1mm REF
X	0.1mm +/-0.1mm

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	500

General Informati	on
Series	T493 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability
Features	High Reliability
RoHS	No
Prop 65	▲ WARNING: Cancer and reproductive harm - http://www.p65warnings.ca.gov.
SCIP Number	1dd2e1b8-26dd-4d52-927c-6f9d519011aa
Termination	Solder Coated
AEC-Q200	No
Component Weight	224.2 mg
Notes	P and R dimensions represents the minimum solderable area of the termination surface entirely below cutout (if one is present).

Specifications	
Capacitance	10 uF
Capacitance Tolerance	10%
Voltage DC	16 VDC (85C), 10.72 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	6% 120Hz 25C
Failure Rate	C (0.01%/1000 Hrs)
Resistance	0.6 Ohms (100kHz 25C)
Ripple Current	428 mA (rms, 100kHz 25C)
Leakage Current	1.6 uA (5min 25°C)
Testing and Reliability	10 Cycles Surge Current Testing At -55C And +85C Before Weibull

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.